PC917X/PC918X

■ Features

1. High speed response

($t_{PHL,tPLH}$: TYP. $0.3 \mu s$ at $R_L = 1.9 k\Omega$)

2. High instantaneous common mode rejection voltage

 $(CM_H: TYP. 1kV/\mu s)$

3. Standard dual-in-line package

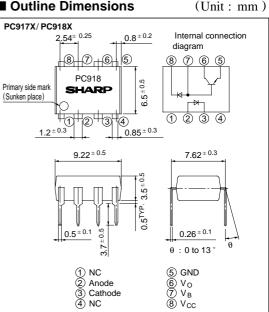
4. Recognized by UL, file No. E64380

■ Applications

- 1. Computers, measuring instruments, controllers
- 2. High speed line receivers high speed logic
- 3. Switing regulators
- 4. Signal transmission between circuits of different potentials and impedances

High Speed, High CMR **OPIC Photocoupler**

■ Outline Dimensions



* "OPIC" (Optical IC) is a trademark of the SHARP Corporation. An OPIC consists of a light-detecting element and signalprocessing circuit integrated onto a single chip.

The marking of PC917 is * PC917 has no base terminal. ((7): NC)

■ Absoulte Maximum Ratings

/ TD	25	\sim
(Ta =	25°	'C)
\ 1 a -	20	\sim

	Parameter	Symbol	Rating	Unit
	Forward current	I_F	25	mA
Input	Reverse voltage	V_R	5	V
	Power dissipation	P	45	mW
	Supply voltage	V _{CC}	- 0.5 to + 15	V
	Output voltage	Vo	- 0.5 to + 15	V
Output	*1Emitter-base voltage	V EBO	5	V
	Output current	Io	8	mA
	Power dissipation	Po	100	mW
*2Isolation voltage		V iso	2 500	V_{rms}
Operating temperature		T opr	- 55 to + 100	°C
Storage temperature		T stg	- 55 to + 125	°C
*3 Soldering temperature		T sol	260	°C

^{*1} Voltage between pin 5 and pin 7 (applies to PC918X)

^{*2 40} to 60% RH, AC for 1 minute

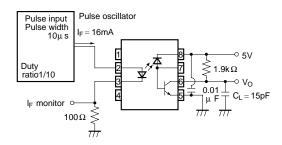
^{*3} For 10 seconds

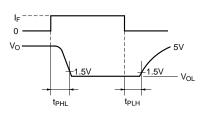
■ Electro-optical Characteristics

(Unless otherwise specified, Ta = 0 to $+ 70^{\circ}C$)

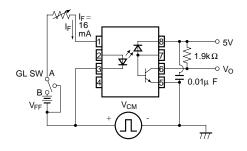
	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Input	Forward voltage	VF	$Ta = 25^{\circ}C$, $I_F = 16mA$	-	1.7	1.95	V
	Reverse current	I_R	$Ta = 25^{\circ}C, V_R = 5V$	-	-	10	μΑ
	Terminal capacitance	Ct	$Ta = 25^{\circ}C, V_F = 0, f = 1MH_Z$	-	60	250	pF
Output	High level output current (1)	$I_{OH(1)}$	$Ta = 25^{\circ}C$, $I_F = 0$, $V_{CC} = V_0 = 5.5V$	-	3	500	nA
	High level output current (2)	$I_{OH(2)}$	$Ta = 25$ °C, $I_F = 0$, $V_{CC} = V_0 = 15V$	-	-	1	μΑ
	High level output current (3)	I _{OH(3)}	$I_F = 0$, $V_{CC} = V_O = 15V$	-	-	50	μΑ
	Low level output voltage	V _{OL}	$I_F = 16mA, I_O = 2.4mA,$ $V_{CC} = 4.5V$	-	-	0.4	V
	Low level supply current	I_{CCL}	$I_F = 16\text{mA}$, $V_O = \text{open}$, $V_{CC} = 15V$	-	200	-	μΑ
	High level supply current (1)	I _{CCH(1)}	$Ta = 25$ °C, $I_F = 0$, $V_O = open$ $V_{CC} = 15V$	-	0.02	1	μΑ
	High level supply current (2)	I _{CCH(2)}	$I_F = 0$, $V_O = open$, $V_{CC} = 15V$	-	-	2	μΑ
Transfer charac- teristics	Current transfer ratio	CTR	$Ta = 25$ °C, $I_F = 16$ mA, $V_O = 0.4$ V, $V_{CC} = 4.5$ V	19	-	-	%
	Isolation resistance	R _{ISO}	Ta = 25°C, DC500V, 40 to 60% RH	5 x 10 ¹⁰	1011	-	Ω
	Floating capacitance	$C_{\rm f}$	$Ta = 25^{\circ}C, V = 0, f = 1MH_{Z}$	-	0.6	1	pF
	*4" High-Low" propagation delay time	t _{PHL}	$Ta = 25$ °C, $R_L = 1.9k\Omega$ $I_F = 16mA$, $V_{CC} = 5V$	-	0.3	0.8	μs
	*4" Low→High" propagation delay time	t PLH	$Ta = 25$ °C, $R_L = 1.9k\Omega$ $I_F = 16mA$, $V_{CC} = 5V$	-	0.3	1.2	μs
	*5Instantaneous common mode rejection voltage "Output: High level"	СМн	$Ta = 25$ °C, $I_F = 0$, $R_L = 1.9k\Omega$ $V_{CM} = 10Vp-p$, $V_{CC} = 5V$	-	1 000	-	V/ μ s
	*5Instantaneous common mode rejection voltage "Output: Low level"	CM _L	$Ta = 25$ °C, $I_F = 16$ mA, $R_L = 1.9$ k Ω $V_{CM} = 10$ Vp-p, $V_{CC} = 5$ V	-	- 1 000	-	V/ μ s

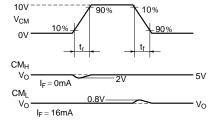
*4 Test Circuit for Propagation Delay Time (PC918X)





*5 Test Circuit for Instantaneous Common Mode Rejection Voltage (PC918X)





When the switch for infrared light emitting diode sets to A.

When the switch for infrared light emitting diode sets to B.

Fig. 1 Forward Current vs. Ambient Temperature

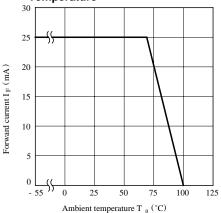


Fig. 3 Forward Current vs. Forward Voltage

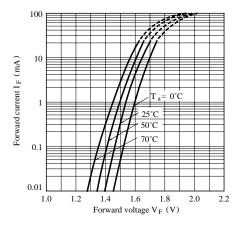


Fig. 5 Relative Current Transfer Ratio vs. Forward Current

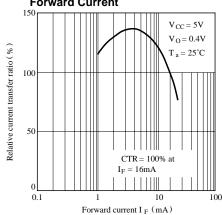


Fig. 2 Power Dissipation vs. Ambient Temperature

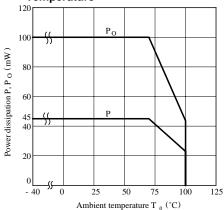


Fig. 4 Output Current vs. Output Voltage

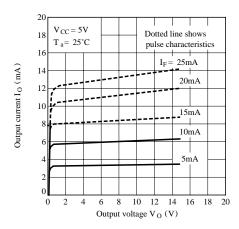


Fig. 6 Relative Current Transfer Ratio vs.
Ambient Temperature

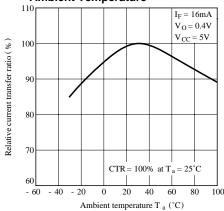


Fig. 7 Propagation Delay Time vs.
Ambient Temperature

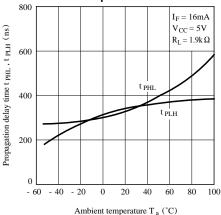


Fig. 9 Frequency Response

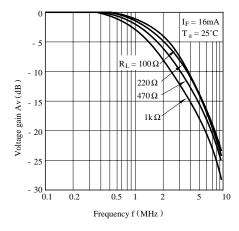
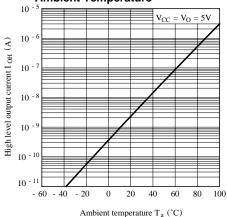
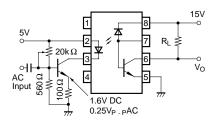


Fig. 8 High Level Output Current vs.
Ambient Temperature



Test Circuit for Frequency Response (PC918X)



■ Precautions for Use

- (1) It is recommended that a by-pass capacitor of more than $0.01 \,\mu$ F is added between V_{cc} and GND near the device in order to stabilize power supply line.
- (2) Transistor of detector side in bipolar configuration is apt to be affected by static electricity for its minute design. When handling them, general counterplan against static electricity should be taken to avoid breakdown of devices or degradation of characteristics.
- (3) As for other general cautions, refer to the chapter "Precautions for Use".

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 - Traffic signals
 - Gas leakage sensor breakers
 - Alarm equipment
 - Various safety devices, etc.
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